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## Semi-conducting mixed-valent $X_4TCNQ^{-I/-II}$ (X = H, F) charge-transfer complexes with $C_6H_2(NH_2)_4$

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# S1 Synthesis

#### $[C_6H_2(NH_2)_4][TCNQ]$

 $[C_6H_2(NH_2)_4]$ [TCNQ] was prepared according to the literature procedure.<sup>1</sup> IR (KBr) v: 2179, 2144 cm<sup>-1</sup>.

#### $[C_6H_2(NH_2)_4][F_4TCNQ]$

A solution of  $F_4TCNQH_2$  (13.9 mg, 0.05 mmol) in methanol (1.5 mL) and N,Ndimethylformamide (0.5 mL) was added to a stirred suspension of  $[C_6H_2(NH_2)_2(NH)_2]$  (6.5 mg, 0.05 mmol) in methanol (1.0 mL). The reaction mixture was stirred for several hours during which time a dark precipitate formed. The solid was collected by filtration and washed with methanol (7.2 mg, 35 %). IR (KBr) v: 2181, 2149 cm<sup>-1</sup>.

Infrared spectra were collected on a Bruker Tensor 27 FT-IR using pressed KBr discs.

## S2 Powder diffraction

Powder x-ray diffraction patterns were collected on either an Oxford Diffraction SuperNova or a XtaLAB Synergy diffractometer. Data were collected on the lab-based instruments using Cu  $K\alpha$  radiation. Data collected were processed with the CrysAlisPro software and a baseline correction performed. Sample temperature was held using a stream of N<sub>2</sub> gas controlled by a Cryostream device.



**Fig. S2.1** Powder diffraction pattern of  $[C_6H_2(NH_2)_4][TCNQ]$ .



**Fig. S2.2** Powder diffraction pattern of  $[C_6H_2(NH_2)_4][F_4TCNQ]$ .

## S3 Kistenmacher relationship calculations

The Kistenmacher relationship can be used to relate selected bond distances within the  $X_4$ TCNQ unit to estimate the charge associated with the  $X_4$ TCNQ species.<sup>2</sup>

The relationship is given by the expression:



Recent work with the dianionic forms of  $X_4$ TCNQ has enabled the calculation of revised values for A and B for both TCNQ (A = -41.667, B = 19.818) and F<sub>4</sub>TCNQ (A = -45.756, B = 21.846).<sup>3</sup> These values have been used to estimate the charge associated with the  $X_4$ TCNQ in the chargetransfer complexes reported.

**Table S3.1** Selected bond lengths within the  $X_4TCNQ$  species of the  $[C_6H_2(NH_2)_4][X_4TCNQ]$  complexes.

CT complex	<b>b</b> (Å)	<i>c</i> (Å)	<i>d</i> (Å)	<i>c</i> /( <i>b</i> + <i>d</i> )	Charge
					( <i>q</i> )
$[C_6H_2(NH_2)_4][TCNQ]$	1.409(4)	1.435(3)	1.411(4)	0.509	-1.39(12)
$[C_6H_2(NH_2)_4][F_4TCNQ]^a$	1.401	1.443	1.412	0.513	-1.63

<sup>a</sup> Bond lengths are from the relaxed dispersion-corrected DFT structure.

#### S4 Infra-red spectroscopic analysis of charge transfer

The general empirical formula:

$$\rho = 2\Delta v / v_0 (1 - v_1^2 / v_0^2)^{-1}$$
where  $\Delta v = v_0 - v_{CT}$ 

has been widely used for both TCNQ<sup>4, 5</sup> and F<sub>4</sub>TCNQ<sup>6, 7</sup> based charge-transfer complexes and relates the infrared frequencies of the localised ( $v_0$ ,  $v_1$ ) and charge-transfer ( $v_{CT}$ ) species to the degree of charge-transfer ( $\rho$ ). The method has been applied to X<sub>4</sub>TCNQ based CT systems in which the X<sub>4</sub>TCNQ acts as an acceptor, however in this current work the X<sub>4</sub>TCNQ species is a donor. As such  $v_0$  is assigned as the localised dianionic state and  $v_1$  as the localised radical anionic state.

Typically, for neutral TCNQ the v(CN) stretches occur at 2225 while for the radical monoanion the v(CN) stretches are lowered to 2187 and 2158 cm<sup>-1</sup>. Further reduction to 2152 and 2104 cm<sup>-1</sup> occurs for the dianion.<sup>1, 8</sup> The nitrile frequencies of  $[C_6H_2(NH_2)_4][TCNQ]$  are 2179 and 2144 cm<sup>-1</sup>. With frequencies of 2152 cm<sup>-1</sup>, 2187 cm<sup>-1</sup> and 2179 cm<sup>-1</sup> for v<sub>0</sub>, v<sub>1</sub> and v<sub>CT</sub> respectively,  $\rho = 0.77$  corresponding to a charge of -1.23. In contrast the electron withdrawing fluorine substituents of F<sub>4</sub>TCNQ, result in nitrile shifts to higher energies, typically at 2225 cm<sup>-1</sup> for the neutral system, 2197 and 2178 cm<sup>-1</sup> for the radical monoanion and at 2167 and 2133 cm<sup>-1</sup> for the dianion.<sup>9, 10, 11, 12</sup> The nitrile frequencies of  $[C_6H_2(NH_2)_4][F_4TCNQ]$  are 2181 and 2149 cm<sup>-1</sup>. With frequencies of 2167 cm<sup>-1</sup>, 2197 cm<sup>-1</sup> and 2181 cm<sup>-1</sup> for v<sub>0</sub>, v<sub>1 and v<sub>CT</sub> respectively,  $\rho = 0.46$  corresponding to a charge of -1.54.</sub>

# S5 Degree of charge transfer (p) and charge (q) of X<sub>4</sub>TCNQ

The  $X_4$ TCNQ species can act as both an electron donor and an electron acceptor. The charge (*q*) on the  $X_4$ TCNQ species can be used to infer the degree of charge transfer (*p*) within the CT complex. Figure S4.1 highlights this case for TCNQ species.



**Fig. S5.1** Degree of charge transfer (*p*) from donor to acceptor represented schematically as function of the charge on the TCNQ species.

## S6 UV-Vis-NIR spectroscopy

Vis-NIR diffuse reflectance spectroscopy was used to analyse powdered samples. The spectrum was collected on a CARY 5000 UV-Vis-NIR spectrophotometer with a Harrick Omni Diff Probe attachment using Varian WinUV software V3.0. The data were recorded from 5000 to 25 000 cm<sup>-1</sup> with a scan rate of 6000 cm<sup>-1</sup> min<sup>-1</sup>. Samples were supported on high density filter paper which was also used to provide the background reference. The Kubelka–Munk transform has been applied to produce a Tauc plot where  $F(R) = (1 - R)^2/2R$  (*R* is the diffuse reflectance of the sample as compared to the background reference).



**Fig. S6.1** Vis-NIR spectra of  $[C_6H_2(NH_2)_4][TCNQ]$ . The axis break corresponds to the discontinuity at the detector changeover.



**Fig. S6.2** Tauc plot for  $[C_6H_2(NH_2)_4][TCNQ]$  CT complex showing the bandgap.

## **S7** Electrical conductivity measurements

Two point conductivity measurements were conducted with an in-house constructed apparatus, with a 2-electrode screw cell design adapted from reference <sup>13</sup>. Pellets of the compound were pressed between two copper dies (contact area 7.069 mm<sup>2</sup>) with two brass screws (see Figure S6.1). Sample thickness was measured with callipers and was in the range of 0.1 mm. The assembled screw cell was placed in an in-house built cryostat to achieve temperature control. I-V profiles were recorded with an Ossila X100 Source Measure Unit.

The conductivity of the material was calculated from the I-V profiles by modelling with

Ohm's law,  $R = \frac{V}{I}$ , where *R* is resistance, *V* is voltage and I is current

The temperature dependence of the conductivity was fitted to the Arrhenius equation,

 $\sigma = \sigma_o e^{\frac{Da}{k_B T}}$ , where  $\sigma$  is the conductivity,  $\sigma_o$  is the pre-exponential factor, Ea is the activation energy,  $k_B$  is the Boltzmann constant and T is the temperature.



Fig. S7.1 Two point screw-cell design used for electrical conductivity measurements.





**Fig. S7.3** I-V curves for the  $[C_6H_2(NH_2)_4][F_4TCNQ]$  compound.

# S8 Computational details, band structure and density of states (DOS) plots

Electronic-structure calculations have been undertaken with the projected augmented wave (PAW) formalism combined with plane-wave based, periodic Density Functional Theory (DFT), as implemented within the Vienna Ab-initio Simulation Package (VASP). <sup>14-16</sup>

The single crystal structure of the  $[C_6H_2(NH_2)_4][TCNQ]$  complex was known.<sup>1</sup> An input file was prepared from crystallographic data with the aid of the Bilbao Crystallographic Server resources. The atomic positions of the  $[C_6H_2(NH_2)_4][TCNQ]$  structure were allowed to relax with fixed lattice constants using the Perdew-Burke-Ernzerhof functional (PBE).<sup>17</sup> As van der Waals effects are expected to influence the structure, Grimme's DFT-D3 dispersion correction with Becke-Johnson damping in its periodic implementation has been applied.<sup>18</sup> The validity of the relaxed structure was supported by comparison of the TCNQ bond lengths to the single crystal structure (Table S8.1). With these values within the expected tolerances for a generalised gradient approximation (GGA) functional,<sup>19</sup> such as PBE(-D3). After preliminary tests – as is common for such cases – a plane-wave cutoff energy of 500 eV was found suitable for convergence of the electronic wave functions to give total energies within an accuracy of 0.01 eV/atom and was used for all calculations. A gamma centered *k*-mesh (5 x 4 x 3) was employed for the structure optimisation.

Crystallographic atomic positional data could not be obtained for  $[C_6H_2(NH_2)_4][F_4TCNQ]$ . Powder x-ray diffraction indicates however that the structure of  $[C_6H_2(NH_2)_4][F_4TCNQ]$  is similar  $[C_6H_2(NH_2)_4][TCNQ].$ The crystallographic to positions from the [C<sub>6</sub>H<sub>2</sub>(NH<sub>2</sub>)<sub>4</sub>][TCNQ] structure were used as initial inputs, with the hydrogen atoms of the TCNQ species replaced with fluorone atoms. The lattice parameters and atomic positions were relaxed with the PBE-D3(BJ) level of theory and a plane wave cutoff energy of 1000 eV which was sufficient to relieve Pulay stress.20 The powder pattern of the [C<sub>6</sub>H<sub>2</sub>(NH<sub>2</sub>)<sub>4</sub>][F<sub>4</sub>TCNQ] relaxed structure compares favourably with the experimental powder pattern for this compound.

Key electronic properties (band structures and density of states) were calculated with singlepoint calculations with the HSE06<sup>21</sup> functional based on the PBE-D3(BJ) optimised structures. Electronic band-structures were calculated along high symmetry points according to the Bilbao Crystallographic Server.<sup>22-24</sup> The density of states were calculated with a gamma centered *k*- mesh (5 x 4 x 3). The separation into partial density of states (PDOS) was carried out with a group-own code.

Band decomposed charge density plots were generated in Visualization for Electronic and STructural Analysis (VESTA, available from <a href="http://jp-minerals.org/vesta/en/">http://jp-minerals.org/vesta/en/</a>).

**Table S8.1**Bond distances of the TCNQ within the  $[C_6H_2(NH_2)_4][TCNQ]$  complex asdetermined by single-crystal X-ray diffraction and solid-state DFT.



**Fig. S8.1** Band structure and DOS for  $[C_6H_2(NH_2)_4][F_4TCNQ]$ .



**Fig. S8.2** Partial density of states plot for  $[C_6H_2(NH_2)_4][TCNQ]$ .



**Fig. S8.3** Partial density of states plot for  $[C_6H_2(NH_2)_4][F_4TCNQ]$ .

Table S8.2	Band gaps and band dispersions for $[C_6H_2(NH_2)_4][TCNQ]$ and
$[C_6H_2(NH_2)_4]$	[F <sub>4</sub> TCNQ].

CT complex	Band gap (eV)	Valence	Conduction	
		bandwidth (eV)	bandwidth (eV)	
$[C_6H_2(NH_2)_4][TCNQ]$	0.49	0.45	0.50	
$[C_6H_2(NH_2)_4][F_4TCNQ]$	0.67	0.36	0.44	

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